



ALPHA & OMEGA
SEMICONDUCTOR

AON3814

20V Dual N-Channel MOSFET

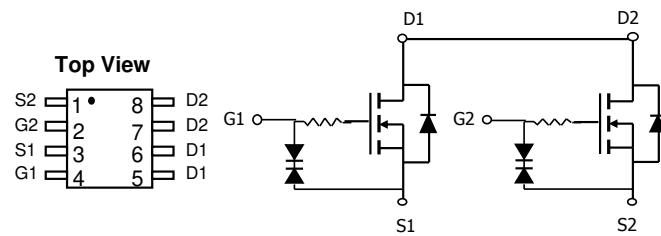
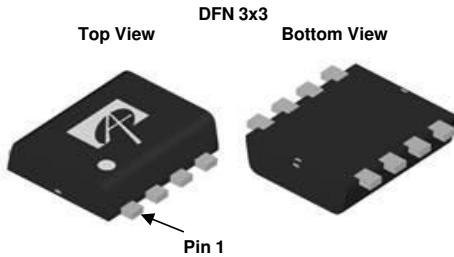
General Description

The AON3814 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V $V_{GS(MAX)}$ rating. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration.

Product Summary

V_{DS}	20V
I_D (at $V_{GS}=4.5V$)	6A
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$)	< 17mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4V$)	< 18.5mΩ
$R_{DS(ON)}$ (at $V_{GS} = 3.1V$)	< 23mΩ
$R_{DS(ON)}$ (at $V_{GS} = 2.5V$)	< 24mΩ

ESD Protected



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ^F	I_D	6	A
$T_C=70^\circ\text{C}$		5.3	
Pulsed Drain Current ^B	I_{DM}	40	
Power Dissipation ^F	P_D	2.5	W
$T_C=70^\circ\text{C}$		1.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	40	50	°C/W
Steady-State		75	95	°C/W
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	30	40	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 10\text{V}$			10	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.3	0.7	1.1	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	40			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=6\text{A}$ $T_J=125^\circ\text{C}$		12.5 18.5	17	$\text{m}\Omega$
		$V_{GS}=4\text{V}, I_D=6\text{A}$		12.9	18.5	$\text{m}\Omega$
		$V_{GS}=3.1\text{V}, I_D=6\text{A}$		14	23	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=6\text{A}$		15.6	24	$\text{m}\Omega$
		$V_{GS}=1.8\text{V}, I_D=6\text{A}$		23		$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=6\text{A}$		33		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.6	1	V
I_S	Maximum Body-Diode Continuous Current				3.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$	730	920	1100	pF
C_{oss}	Output Capacitance		110	155	200	pF
C_{rss}	Reverse Transfer Capacitance		45	75	105	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2.4		k Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=6\text{A}$	8.8	11	13	nC
Q_{gs}	Gate Source Charge		1.6	2	2.4	nC
Q_{gd}	Gate Drain Charge		1.9	3.2	4.5	nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=5\text{V}, V_{DS}=10\text{V}, R_L=1.7\Omega, R_{\text{GEN}}=3\Omega$		0.3		μs
t_r	Turn-On Rise Time			0.6		μs
$t_{\text{D(off)}}$	Turn-Off DelayTime			7.9		μs
t_f	Turn-Off Fall Time			4.4		μs

A. The value of $R_{\text{IJ(A)}}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

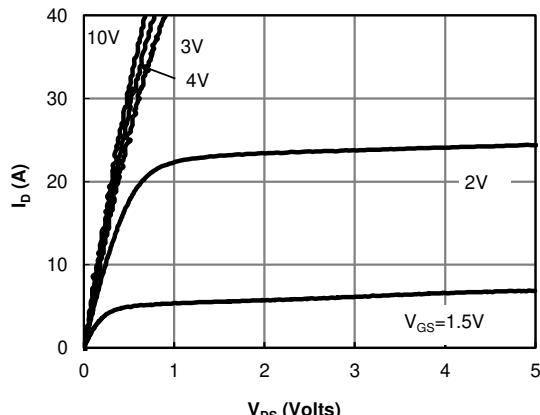
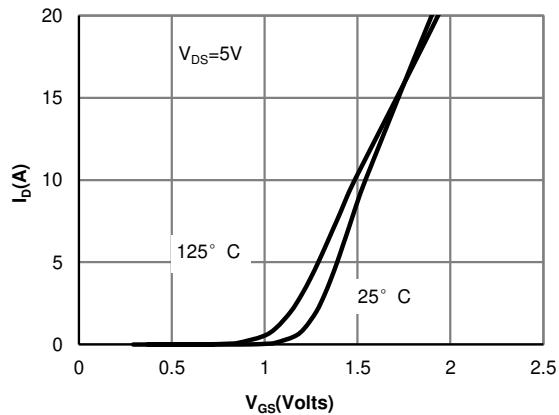
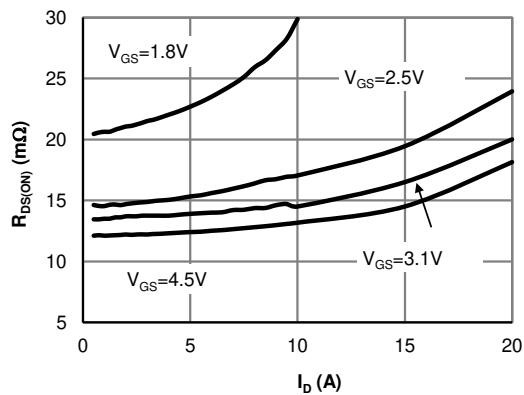
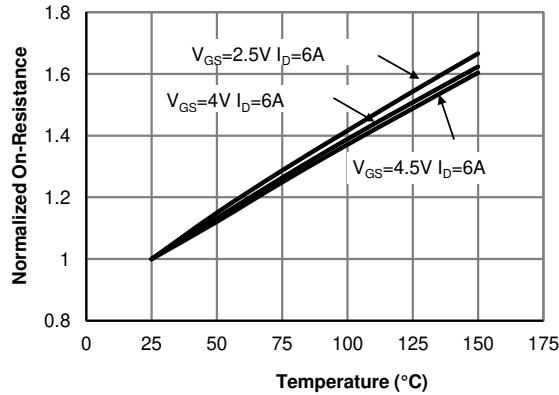
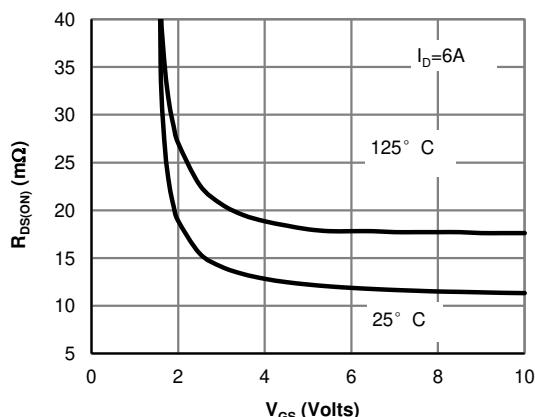
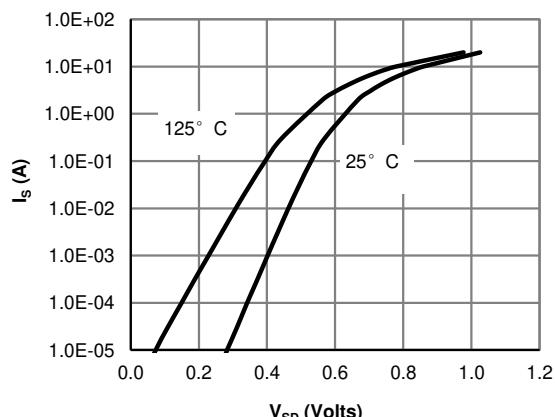
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

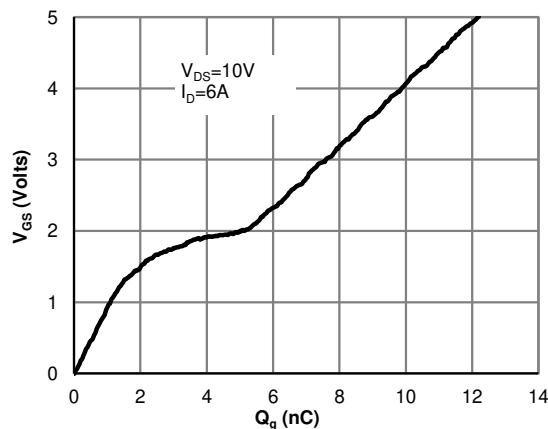
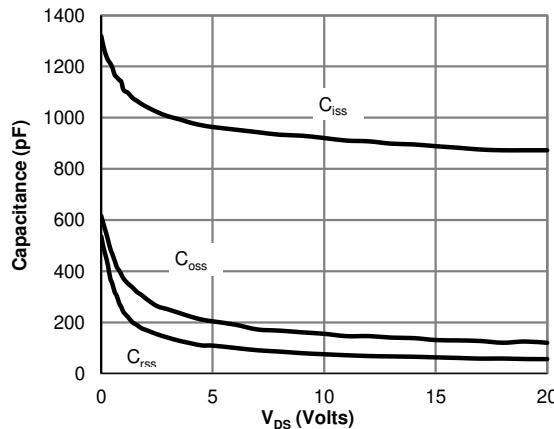
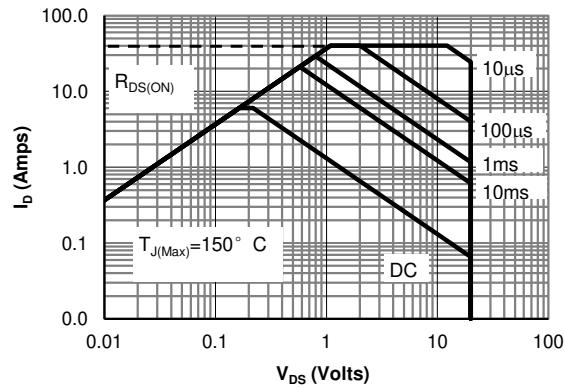
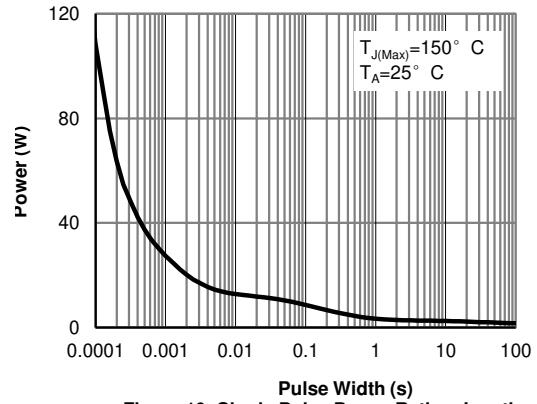
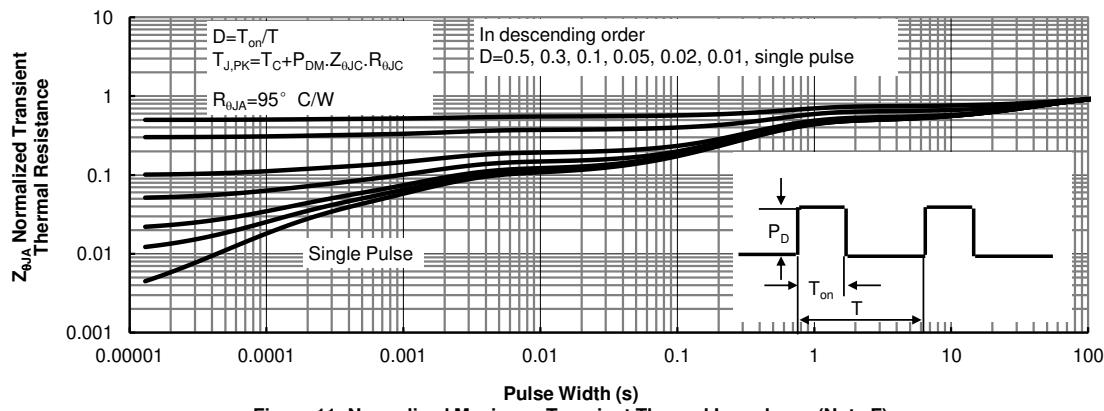
D. The $R_{\text{IJ(A)}}$ is the sum of the thermal impedance from junction to lead R_{IJL} and lead to ambient.

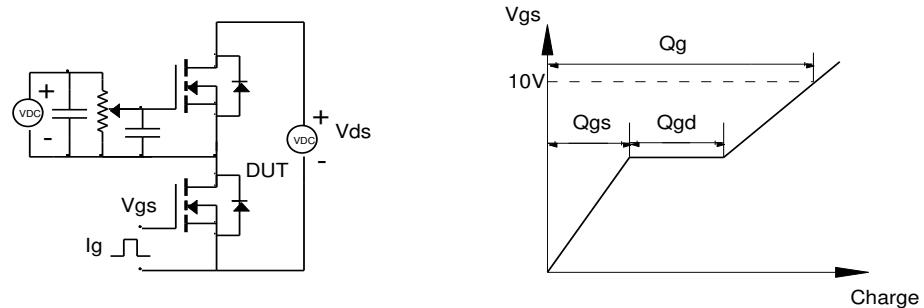
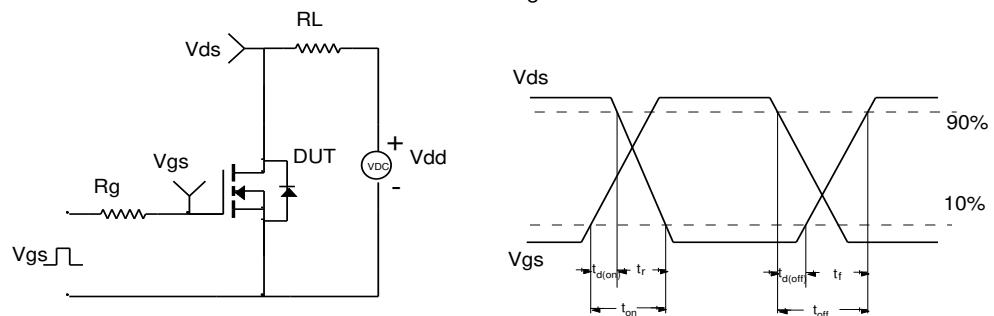
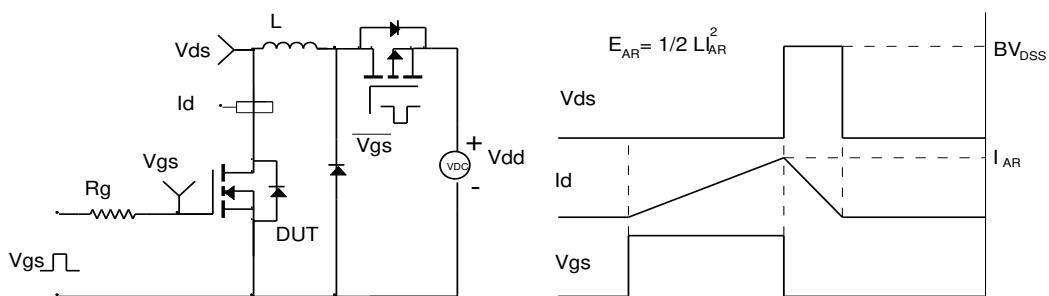
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
